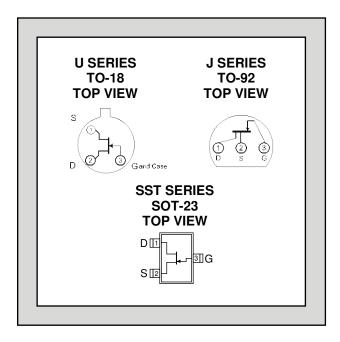


Improved Standard Products®

FEATURES									
Direct Replacement For SILICONIX U/J/SST308 SERIES									
OUTSTANDING HIGH FREQUENCY GAIN Gpg = 11.5dE									
LOW HIGH FREQUENCY NOISE	NF = 2.7dB								
ABSOLUTE MAXIMUM RATINGS ¹									
@ 25 °C (unless otherwise stated)									
Maximum Temperatures									
Storage Temperature -55 to 150°C									
Junction Operating Temperature	-55 to 150°C								
Maximum Power Dissipation									
Continuous Power Dissipation (J/SST) ⁴	350mW								
Continuous Power Dissipation (U) ⁵	500mW								
Maximum Currents									
Gate Current (J/SST)	10mA								
Gate Current (U)	20mA								
Maximum Voltages									
Gate to Drain	-25V								
Gate to Source	-25V								

U/J/SST308 SERIES

SINGLE N-CHANNEL HIGH FREQUENCY JFET AMPLIFIER



COMMON ELECTRICAL CHARACTERISTICS @ 25 °C (unless otherwise stated)

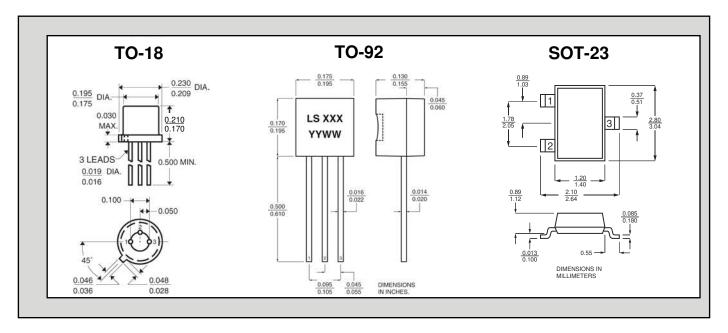
SYMBOL	CHARACTERISTIC		MIN	TYP	MAX	UNIT	CONDITIONS		
BV _{GSS}	Gate to Source Breakdown Voltage		-25			V	$I_G = -1 \mu A, \ V_{DS} = 0 V$		
$V_{\text{GS}(F)}$	Gate to Source Forward Voltage		0.7		1.15	V	$I_G = 10 \text{mA}, V_{DS} = 0 \text{V}$		
lg	Gate Operating Current			-15		рA	$V_{DG} = 9V$, $I_D = 10mA$		
r _{DS(on)}	Drain to Source On Resistance			35		Ω	$V_{GS} = 0V$, $I_D = 1mA$		
e n	Equivalent Noise Voltage			6		nV/√Hz	$V_{DS} = 10V, I_{D} = 10mA, f = 100Hz$		
NF	Noise Figure	<i>f</i> = 105MHz		1.5		dB	V _{DS} = 10V, I _D = 10mA		
INF		<i>f</i> = 450MHz		2.7					
C	Power Gain ²	<i>f</i> = 105MHz		16					
G_{pg}		f = 450MHz		11.5					
~.	Forward Transconductance	f = 105MHz		14					
G fg		<i>f</i> = 450MHz		13		mS			
g og	Output Conductance	f = 105MHz		0.16					
9 09	Carpar Conductance	f = 450MHz		0.55					
IGSS	Gate Reverse Current				-1	nA	$V_{GS} = -15V$, $V_{DS} = 0V$		

SPECIFIC ELECTRICAL CHARACTERISTICS @25 °C (unless otherwise stated)

CVM	YM. CHARACTERISTIC	ТҮР	J/SST308		J/SST309		J/SST310		UNIT	CONDITIONS
STIVI.			MIN	MAX	MIN	MAX	MIN	MAX	UNII	CONDITIONS
$V_{\text{GS(off)}}$	Gate to Source Cutoff Voltage		-1	-6.5	-1	-4	-2	-6.5	V	$V_{DS} = 10V$, $I_D = 1nA$
IDSS	Source to Drain Saturation Current ³		12	75	12	30	24	75	mA	$V_{\text{DS}} = 10 V, V_{\text{GS}} = 0 V$
Ciss	Input Capacitance	4							pF	$V_{DS} = 10V, V_{GS} = -10V$ f = 1MHz
Crss	Reverse Transfer Capacitance	1.9								
g fs	Forward Transconductance	14	8		10		8		mS	$V_{DS} = 10V, I_{D} = 10mA$
gos	Output Conductance	110		250		250		250	μS	f = 1 kHz

SPECIFIC ELECTRICAL CHARACTERISTICS @25 °C (unless otherwise stated)

SYM.	CHARACTERISTIC	ТҮР	U308		U309		U310		UNIT	CONDITIONS
			MIN	MAX	MIN	MAX	MIN	MAX	וואוט	CONDITIONS
V _{GS(off)}	Gate to Source Cutoff Voltage		-1	-6.5	-1	-4	-2.5	-6.5	V	$V_{DS} = 10V$, $I_D = 1nA$
IDSS	Source to Drain Saturation Current ³		12	75	12	30	24	75	mA	$V_{DS} = 10V$, $V_{GS} = 0V$
Ciss	Input Capacitance	4		5		5		5	pF	$V_{DS} = 10V, V_{GS} = -10V$ f = 1MHz
Crss	Reverse Transfer Capacitance	1.9		2.5		2.5		2.5		
g fs	Forward Transconductance	14	10		10		10	·	mS	$V_{DS} = 10V, I_{D} = 10mA$
gos	Output Conductance	110		250		250		250	μS	f = 1 kHz



NOTES

- 1. Absolute maximum ratings are limiting values above which serviceability may be impaired.
- 2. Measured at optimum input noise match
- 3. Pulse test: PW ≤ 300µs, Duty Cycle ≤ 3%
- 4. Derate 2.8mW/°C above 25°C
- 5. Derate 4mW/ºC above 25ºC

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